

## PowerMOS transistor

## BUK417-500AE/BE

## GENERAL DESCRIPTION

N-channel enhancement mode field-effect power transistor in ISOTOP envelope.

The device is intended for use in Switched Mode Power Supplies (SMPS), motor control, welding, DC/DC and AC/DC converters, and in general purpose switching applications.

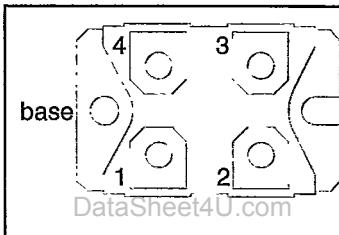
## QUICK REFERENCE DATA

SYMBOL	PARAMETER	MAX.	MAX.	UNIT
$V_{DS}$	BUK417	-500AE	-500BE	V
$I_D$	Drain-source voltage	500	500	
$P_{tot}$	Drain current (DC)	32	28	A
$R_{DS\ ON}$	Total power dissipation	310	310	W
	Drain-source on-state resistance	0.13	0.16	$\Omega$

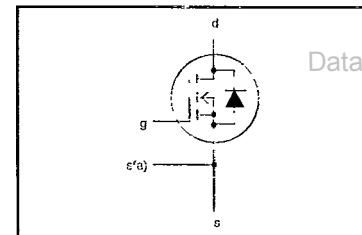
## PINNING - SOT227B

PIN	DESCRIPTION
1	source
2	gate
3	drain
4	ancillary source
base	isolated

## PIN CONFIGURATION



## SYMBOL



## LIMITING VALUES

Limiting values in accordance with the Absolute Maximum System (IEC 134)

SYMBOL	PARAMETER	CONDITIONS	MIN.	MAX.	UNIT
$V_{DS}$ $V_{GDR}$ $\pm V_{GS}$	Drain-source voltage	$R_{GS} = 20\text{ k}\Omega$	-	500	V
	Drain-gate voltage		-	500	V
	Gate-source voltage		-	30	V
$I_D$ $I_b$ $I_{DM}$	Drain current (DC)	$T_{rb} = 25^\circ\text{C}$ $T_{rt} = 100^\circ\text{C}$ $T_{mb} = 25^\circ\text{C}$	-	32	A
	Drain current (DC)		-	20	A
	Drain current (pulse peak value)		-	128	A
$I_{SA,M}$	Ancillary source current (pulse peak value)	$T_{rb} = 25^\circ\text{C}$	-	5.0	A
	Total power dissipation		-	310	W
	Storage temperature		-40	150	°C
$T_s$	Junction Temperature	-	-	150	°C

## THERMAL RESISTANCES

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
$R_{th\ J-mb}$	Thermal resistance junction to mounting base	with heatsink compound	-	-	0.40	K/W
$R_{th\ mb-s}$	Thermal resistance mounting base to heatsink		-	0.05	-	K/W

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**STATIC CHARACTERISTICS** $T_{mb} = 25^\circ C$  unless otherwise specified

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
$V_{(BR)DSS}$	Drain-source breakdown voltage	$V_{GS} = 0 V; I_D = 1.0 \text{ mA}$	500	-	-	V
$V_{GS(TO)}$	Gate threshold voltage	$V_{DS} = V_{GS}; I_D = 1 \text{ mA}$	2.1	3.0	4.0	V
$I_{DSS}$	Zero gate voltage drain current	$V_{DS} = 500 V; V_{GS} = 0 V; T_J = 25^\circ C$	-	20	100	$\mu\text{A}$
$I_{DSS}$	Zero gate voltage drain current	$V_{DS} = 500 V; V_{GS} = 0 V; T_J = 125^\circ C$	-	0.5	5.0	mA
$I_{GSS}$	Gate source leakage current	$V_{GS} = \pm 30 V; V_{DS} = 0 V$	-	10	200	nA
$R_{DS(ON)}$	Drain-source on-state resistance	$V_{GS} = 10 V; BUK417-500AE$ $I_D = 16 A; BUK417-500BE$	-	0.11	0.13	$\Omega$
			-	0.14	0.16	$\Omega$

**DYNAMIC CHARACTERISTICS** $T_{mb} = 25^\circ C$  unless otherwise specified

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
$g_{fs}$	Forward transconductance	$V_{DS} = 25 V; I_D = 16 A$	15.0	30.0	-	s
$C_{iss}$	Input capacitance	$V_{GS} = 0 V; V_{DS} = 25 V; f = 1 \text{ MHz}$	-	7.5	9.0	nF
$C_{oss}$	Output capacitance		-	0.85	1.35	nF
$C_{rss}$	Feedback capacitance		-	350	600	pF
$t_{d(on)}$	Turn-on delay time	$V_{DD} = 30 V; I_D = 2.8 A;$	-	80	120	ns
$t_r$	Turn-on rise time	$V_{GS} = 10 V; R_{GS} = 50 \Omega;$	-	200	300	ns
$t_{d(off)}$	Turn-off delay time	$R_{gen} = 50 \Omega$	-	1100	1350	ns
$t_f$	Turn-off fall time	Resistive Load	-	250	350	ns
$t_{d(on)}$	Turn-on delay time	$V_{DD} = 250 V; I_D = 32 A;$	-	40	80	ns
$t_r$	Turn-on rise time	$V_{GS} = 10 V; R_{gen} = 3.3 \Omega$	-	70	100	ns
$t_{d(off)}$	Turn-off delay time	Resistive Load	-	300	350	ns
$t_f$	Turn-off fall time		-	100	150	ns
$L_d$	Internal drain inductance	Measured from contact screw on terminal 3 to centre of die	-	5	-	nH
$L_s$	Internal source inductance	Measured from contact screw on terminal 1 to source bond pad	-	5	-	nH

**ISOLATION** $T_{mb} = 25^\circ C$  unless otherwise specified

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
$V_{isol}$	R.M.S. voltage from terminals to mounting base	Sinusoidal voltage waveform; $f = 50 - 60 \text{ Hz}$	-	-	2500	V
$C_{isol}$	Capacitance from T3 to mounting base	$f = 1 \text{ MHz}$	-	45	-	pF

**REVERSE DIODE LIMITING VALUES AND CHARACTERISTICS** $T_{mb} = 25^\circ C$  unless otherwise specified

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
$I_{DR}$	Continuous reverse drain current	-	-	-	32	A
$I_{DRM}$	Pulsed reverse drain current	-	-	-	128	A
$V_{SD}$	Diode forward voltage	$I_F = 32 A; V_{GS} = 0 V$	-	1.1	1.4	V
$t_{rr}$	Reverse recovery time	$I_F = 32 A; -dI_F/dt = 100 \text{ A}/\mu\text{s}$	-	0.6	-	$\mu\text{s}$
$Q_{rr}$	Reverse recovery charge	$V_{GS} = 0 V; V_R = 100 V$	-	12	-	$\mu\text{C}$

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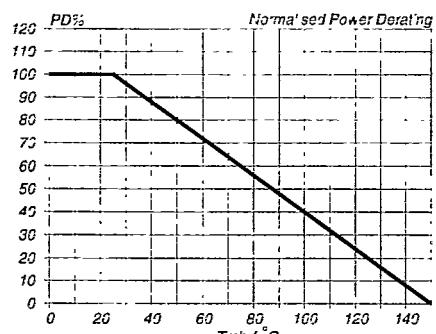


Fig.1. Normalised power dissipation.  
 $PD\% = 100 \cdot P_D / P_{D,25^\circ C} = f(T_{mb})$

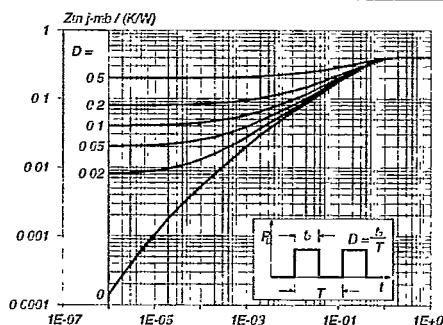


Fig.4. Transient thermal impedance.  
 $Z_{th,jmb} = f(t)$ ; parameter  $D = t_p/T$

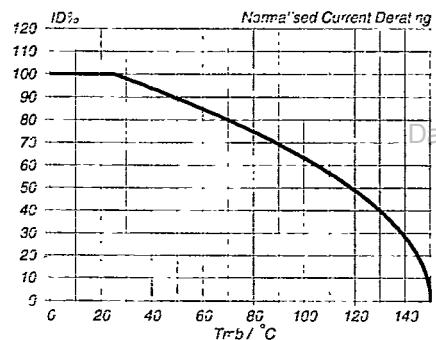


Fig.2. Normalised continuous drain current.  
 $ID\% = 100 \cdot I_D / I_{D,25^\circ C} = f(T_{mb})$ ; conditions:  $V_{GS} \geq 10 \text{ V}$

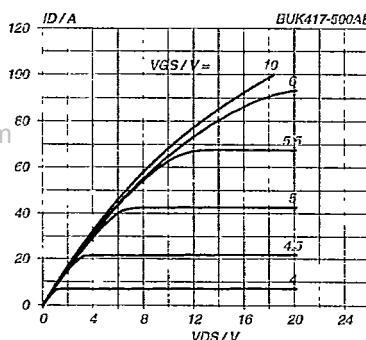


Fig.5. Typical output characteristics,  $T_j = 25 \text{ }^\circ\text{C}$ .  
 $I_D = f(V_{DS})$ ; parameter  $V_{GS}$

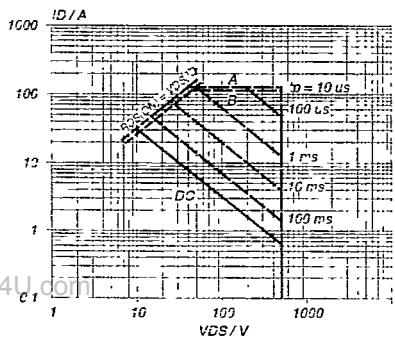


Fig.3. Safe operating area.  $T_{mb} = 25 \text{ }^\circ\text{C}$   
 $I_D \& I_{DM} = f(V_{DS})$ ;  $I_{DM}$  single pulse; parameter  $t_p$

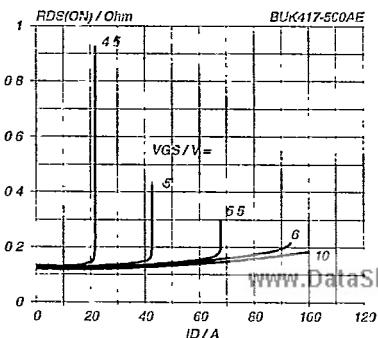
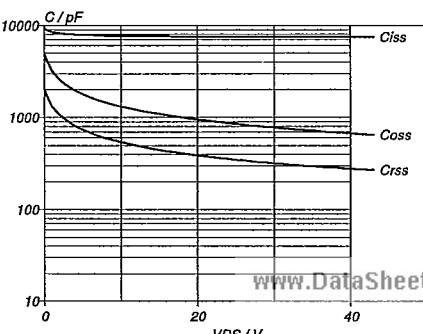
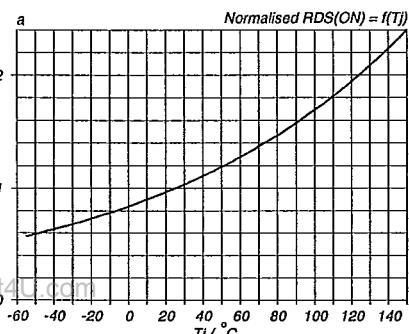
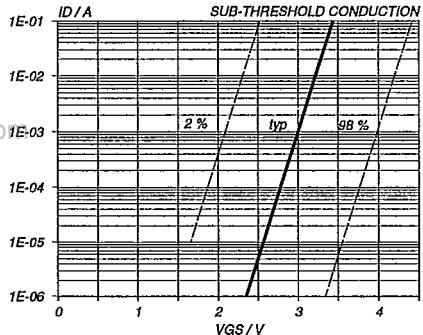
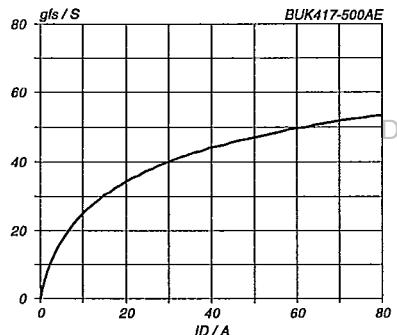
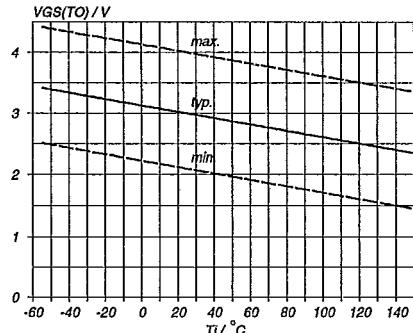
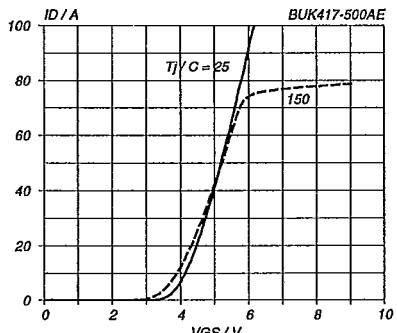


Fig.6. Typical on-state resistance,  $T_j = 25 \text{ }^\circ\text{C}$ .  
 $R_{DS(ON)} = f(I_D)$ ; parameter  $V_{GS}$

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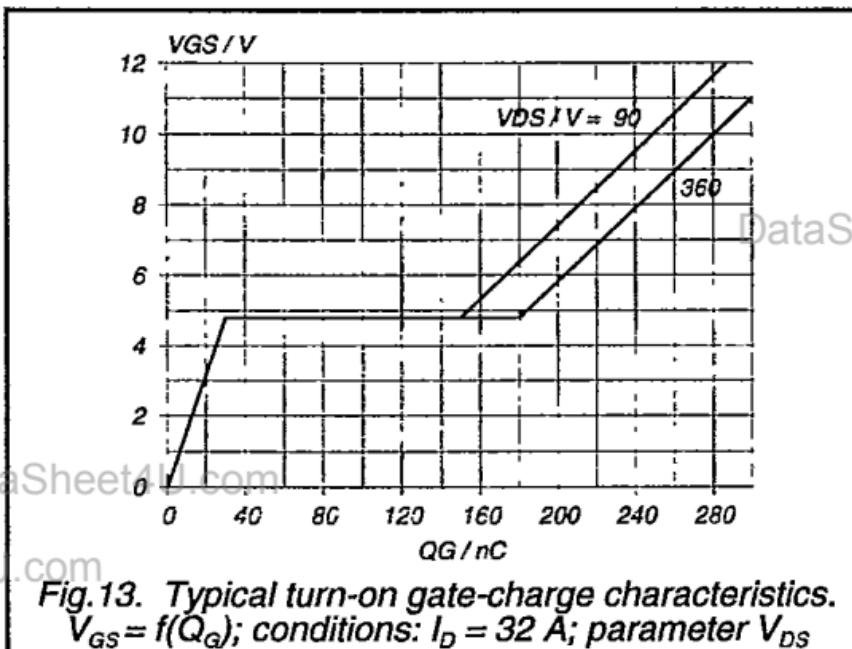


Fig.13. Typical turn-on gate-charge characteristics.  
 $V_{GS} = f(Q_G)$ ; conditions:  $I_D = 32 \text{ A}$ ; parameter  $V_{DS}$

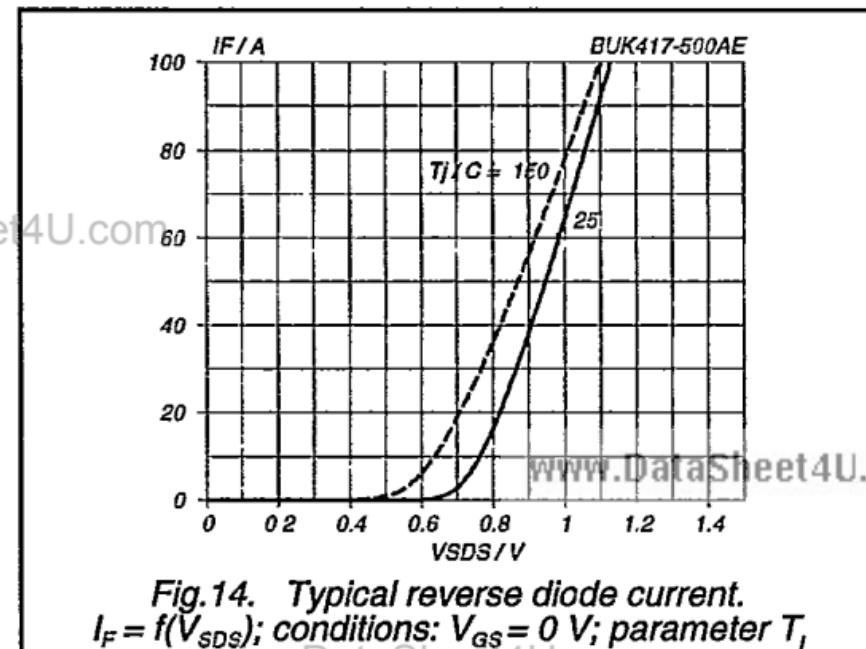


Fig.14. Typical reverse diode current.  
 $I_F = f(V_{SDS})$ ; conditions:  $V_{GS} = 0 \text{ V}$ ; parameter  $T_j$